

<b>Notice of References Cited</b>	Application/Control No. 10/036,527	Applicant(s)/Patent Under Reexamination TERANOSHITA, MASAhide	
	Examiner Thierry L. Pham	Art Unit 2624	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2005/0088677	04-2005	Hayashi, Eiji	358/001.13
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**NON-PATENT DOCUMENTS**

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